

5. The experiments reported in the Excel spreadsheet shown in Exhibit A2 show actual reduction to practice in the United States of the claimed subject matter prior to October 16, 2003;

7. The experiment labeled as FSN-18 in Exhibit A2 utilized a N_2O to a total flow ratio of 0.1714. The resultant film had a low dielectric constant of 2.82 and a thickness of 11375 Å. The measurement was completed prior to October 16, 2003, as shown in the first row of measurement data illustrated in Exhibit B;

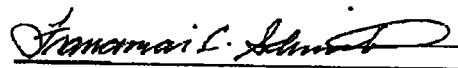
9. The experiment picked in the data line immediately under labeled FSN-17 in Exhibit A2 utilized a N_2O to a total flow ratio of 0.4762. The resultant film had a low dielectric constant of 2.81 and having a thickness of 8145 Å. The measurement was completed prior to October 16, 2003, as shown in substrate measurement map illustrated in Exhibit C;

11. We diligently pursued the subject matter of the pending claims from a time

beginning before October 16, 2003 until filing of the present application on March 29, 2004.

We further declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further, that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

Date: January 16th, 2008



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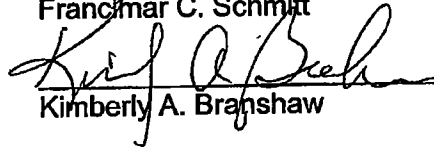
Hichem M'Saad

beginning before October 16, 2003 until filing of the present application on March 29, 2004.

We further declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further, that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

Date: 1/15/08

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